Contents

List of Figures x List of Tables xvi Preface xvii

1 Basics of Material Characterization Techniques 1

۲

- 1.1 Introduction 1
- 1.2 Electromagnetic Spectrum 2
- 1.3 Fundamentals of Crystallography 4
- 1.4 Molecular Vibrations 10
- 1.5 Magnetism in Solids 10
- 1.6 Optical Properties of Solids 11 References 13

2 X-ray Diffraction 15

- 2.1 Introduction 15
- 2.2 Bragg's Law 17
- 2.3 Von Laue Treatment: Laue's Equation 18
- 2.4 Experimental Techniques 20
- 2.4.1 Laue Method 20
- 2.4.2 Rotating Crystal Method 20
- 2.4.3 Powder Method 21
- 2.5 Geometry and Instrumentation 21
- 2.6 Standard XRD Pattern 26
- 2.7 Applications 27
- 2.7.1 Orientation of Single Crystals 27
- 2.7.2 Structure of Polycrystalline Aggregates 29
- 2.7.3 XRD in the Pharmaceutical Field and Forensic Science 33
- 2.7.4 XRD in the Geological Field 34
- 2.8 Examples and Illustrations 34
- 2.8.1 XRD Data and Interpretation in the $PrFe_{1-x}Mn_xO_3$ System 34

 (\bullet)

\v

vi	Contents

2.8.2 XRD Data and Interpretation in the $La_{1-x}Ca_xMnO_3$ System 37

۲

2.8.3 XRD Analysis of $EuFe_{1-x}Mn_xO_3$ (x = 0.0, 0.3, 0.5) 38 References 40

3 Raman Spectroscopy 43

- 3.1 Introduction 43
- 3.2 Infrared and Raman Spectroscopy 44
- 3.3 Raman Spectra: Origin 45
- 3.4 Classical Theory of Raman Scattering 47
- 3.5 Quantum Theory of Raman Spectroscopy 48
- 3.6 Raman Spectrometer 50
- 3.6.1 Excitation Source 50
- 3.6.2 Sample Illumination 51
- 3.6.3 Wavelength Selector 51
- 3.6.4 Detection and Control System 52
- 3.7 Resonance Raman Spectroscopy 53
- 3.8 Special Techniques 55
- 3.8.1 High-pressure Raman Spectroscopy 55
- 3.8.2 Raman Microscopy 57
- 3.8.3 Surface-enhanced Raman Spectroscopy 59
- 3.8.4 Raman Spectroelectrochemistry 60
- 3.9 Applications and Illustrations 62
- 3.9.1 Raman Spectra of the $PrFe_{1-x}Mn_xO_3$ System at Different Concentrations of Mn Doped in Place of Fe 62
- 3.9.2 Raman Spectra and Measurements of the $La_{1-x}Ca_xMnO_3$ System (x = 0.0, 0.3, 0.5, and 0.7) 64
- 3.9.3 Temperature-dependent Raman Study of $La_{1-x}Ca_xMnO_3$ (x = 0.0 and 0.3) 66

References 71

4 X-ray Spectroscopic Techniques 77

- 4.1 X-ray Absorption Spectroscopy 77
- 4.1.1 Introduction 77
- 4.1.2 Basic Principle of XAS 78
- 4.1.3 Experimental Aspects 83
- 4.1.3.1 Synchrotron Radiation 83
- 4.1.3.2 Experimental Setup 84
- 4.1.3.3 Transmission Mode 84
- 4.1.3.4 Fluorescence Mode 85
- 4.1.3.5 Electron Yield Mode 85
- 4.1.4 Examples and Analysis *86*
- 4.1.4.1 X-ray Absorption Spectra of $La_{1-x}Ca_xMnO_3$ (x = 0.0, 0.3, 0.5, 0.7) Samples 86

()

۲

Contents vii

4.1.4.2 Electronic Structure of PrFe_{1-x}Mn_xO₃ by X-Ray Absorption Spectroscopy *88*

۲

- 4.2 X-ray Photoelectron Spectroscopy (XPS) 92
- 4.2.1 Introduction 92
- 4.2.2 Basic Principle 93
- 4.2.3 Energy Referencing 94
- 4.2.4 Instrumentation 96
- 4.2.5 XPS Spectra and Their Features 97
- 4.3 Auger Electron Spectroscopy 99
- 4.3.1 Introduction 99
- 4.3.2 Interactions of Electrons with Matter 100
- 4.3.3 Competition Between X-ray and Auger Electron Emissions 100
- 4.3.4 Auger Process 101
- 4.3.5 Kinetic Energy of the Auger Electron 103
- 4.3.6 Auger Spectra 104
- 4.3.7 Instrumentation 105 References 106

5 Magnetic Measurements 109

- 5.1 Introduction 109
- 5.2 Magnetization Measuring Instruments 111
- 5.2.1 Extraction Technique 112
- 5.2.2 Vibrating Sample Magnetometer 113
- 5.2.3 SQUID Magnetometer 114
- 5.3 Advantages and Disadvantage of a Vibrating Sample Magnetometer 115
- 5.4 Susceptibility Measurement 116
- 5.5 Examples and Illustrations 117
- 5.5.1 Magnetic Behavior Shown by Thin Films of the $PrFe_{1-x}Mn_xO_3$ System Deposited on Substrate Si (100) 117
- 5.5.2 Magnetic Behavior of the $La_{1-x}Ca_xMnO_3$ System Where x is the Concentration of Ca as Dopant and Equals 0.0, 0.3, 0.5, or 0.7 120
- 5.5.3 Magnetic Behavior of $La_{1-x}Ca_xMnO_3$ Thin Films Deposited on Si(100) with x = 0.0, 0.3, 0.5, and 0.7 Being the Concentrations of Ca 124 References 125

6 Dielectric Measurements 129

- 6.1 Introduction 129
- 6.2 Polarization and Dielectric Constant 130
- 6.2.1 Electronic or Optical Polarization 131
- 6.2.2 Orientational Polarization 134
- 6.2.3 Atomic Polarizability 135
- 6.2.4 Interfacial Polarization 136
- 6.3 Mechanism for the Colossal Dielectric Response 137

(

viii Contents

- 6.4 Frequency Dependence of Polarizability 138
- 6.5 Classification of Dielectric Materials 138
- 6.5.1 Nonferroelectric Materials 138
- 6.5.2 Nonpolar Materials 139
- 6.5.3 Polar Materials *139*
- 6.5.4 Dipolar Materials 139
- 6.6 Dielectric Dispersion: A Brief Discussion 140
- 6.7 Dielectric Loss and Relaxation 141
- 6.8 Complex Permittivity 141
- 6.9 Polarization Buildup *142*
- 6.10 Jonscher's Universal Law 145
- 6.11 Examples and Illustrations 148
- 6.11.1 Dielectric Behavior of $PrFe_{1-x}Mn_xO_3$ with x = 0.0, 0.1, 0.3, and 0.5 Being the Concentration of Mn Doped in a Pristine Compound 148

۲

- 6.11.1.1 Frequency and Temperature Dependence of Dielectric Properties 148
- 6.11.2 Dielectric Properties of the $EuFe_{1-x}Mn_xO_3$ System in Which Different Concentrations of Mn Are Doped in $EuFeO_3$ 151
- 6.11.2.1 Dependence of Dielectric Behavior on Frequency 151
- 6.11.2.2 Dependence of Dielectric Behavior on Temperature 154 References 157

7 Electron Microscopy 159

- 7.1 Introduction 159
- 7.2 Generation of an Electron Beam 159
- 7.3 Interaction of an Electron Beam with a Sample 160
- 7.4 Inelastic Scattering and Absorption 161
- 7.5 The Family of Electron Microscopes 164
- 7.5.1 The X-ray Microscope 165
- 7.5.2 The Transmission Electron Microscope 166
- 7.5.3 The Scanning Electron Microscope 172
- 7.5.4 The Scanning Transmission Electron Microscope 174
- 7.6 Atomic Force Microscopy 175
- 7.7 Examples and Illustrations 177
- 7.7.1 AFM Studies of $PrFe_{1-x}Mn_xO_3$ (x = 0.0, 0.1, 0.3, 0.5) Thin Films Grown on Si (100) 177
- 7.7.2 Atomic Force Microscopy in the Case of $La_{1-x}Ca_xMnO_3$ for (a) x = 0.0, (b) x = 0.3, (c) x = 0.5, and (d) x = 0.7 177
- 7.7.3 Morphological Studies and Elemental Analysis of $EuFe_{1-x}Mn_xO_3$ (x = 0.0, 0.3, and 0.5) 178 References 181

()

Contents ix

- 8 Infrared Spectroscopy 183
- 8.1 Introduction 183
- 8.2 Instrumentation for FTIR 184

۲

- 8.3 Fourier Transform 189
- 8.4 Electromagnetic Radiation 190
- 8.5 Infrared Absorption 190
- 8.6 Normal Modes of Vibration 191
- 8.7 Complicating Factors 192
- 8.8 Applications of IR Spectroscopy 192
- 8.8.1 Food Science 192
- 8.8.2 Chemistry in Clinical Practice 193
- 8.8.3 Plants 194
- 8.8.4 Disease Diagnosis 194
- 8.8.5 Environmental Applications 195 References 196

Index 199

۲

۲